

# Accepted Manuscript

A consistent full-field integrated DIC framework for HR-EBSD

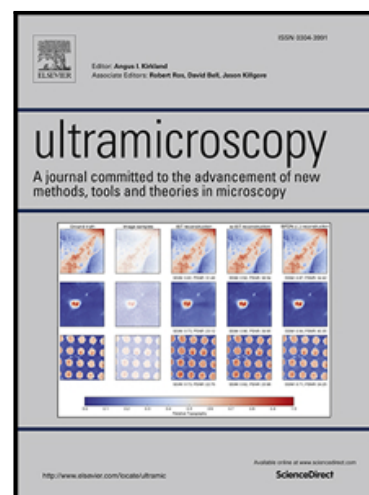
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**Highlights**

- A general, finite-strain Integrated DIC framework for HR-EBSD was developed.
- One-step correlation of the full field-of-view of EBSPs without filtering or remapping.
- High strain accuracy ( $\sim 1 \times 10^{-5}$ ) for large rotations up to  $10^\circ$ , rivaling state-of-the-art HR-EBSD.
- High robustness / fast convergence from  $1^\circ$  misorientations with noise up to 20% / 5%.

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